



RF Power Field Effect Transistor

N-Channel Enhancement-Mode Lateral MOSFET

Designed for pulsed wideband applications operating at frequencies between 3100 and 3500 MHz.

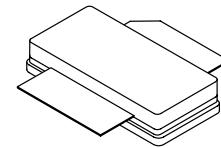
- Typical Pulsed Performance: $V_{DD} = 32$ Volts, $I_{DQ} = 150$ mA, $P_{out} = 120$ Watts Peak (24 Watts Avg.), Pulsed Signal, $f = 3500$ MHz, Pulse Width = 100 μ sec, Duty Cycle = 20%
Power Gain — 12 dB
Drain Efficiency — 40%
- Typical WiMAX Performance: $V_{DD} = 32$ Volts, $I_{DQ} = 900$ mA, $P_{out} = 18$ Watts Avg., $f = 3500$ MHz, 802.16d, 64 QAM $^{3/4}$, 4 Bursts, 7 MHz Channel Bandwidth, Input Signal PAR = 9.5 dB @ 0.01% Probability on CCDF
Power Gain — 13 dB
Drain Efficiency — 16%
RCE — -33 dB (EVM — 2.2% rms)
- Capable of Handling 10:1 VSWR, @ 32 Vdc, 3300 MHz, 120 Watts Peak Power
- Capable of Handling 3 dB Overdrive @ 32 Vdc

Features

- Characterized with Series Equivalent Large-Signal Impedance Parameters
- Internally Matched for Ease of Use
- Qualified Up to a Maximum of 32 V_{DD} Operation
- Integrated ESD Protection
- Greater Negative Gate-Source Voltage Range for Improved Class C Operation
- RoHS Compliant
- In Tape and Reel. R3 Suffix = 250 Units per 56 mm, 13 inch Reel.

MRF7S35120HSR3

**3100-3500 MHz, 120 W PEAK, 32 V PULSED
LATERAL N-CHANNEL RF POWER MOSFET**



**CASE 465A-06, STYLE 1
NI-780S**

Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain-Source Voltage	V_{DSS}	-0.5, +65	Vdc
Gate-Source Voltage	V_{GS}	-6.0, +10	Vdc
Storage Temperature Range	T_{stg}	-65 to +150	°C
Case Operating Temperature	T_C	150	°C
Operating Junction Temperature (1,2)	T_J	225	°C

Table 2. Thermal Characteristics

Characteristic	Symbol	Value (2,3)	Unit
Thermal Resistance, Junction to Case Case Temperature 79°C, 120 W Pulsed, 100 μ sec Pulse Width, 20% Duty Cycle Case Temperature 72°C, 120 W Pulsed, 500 μ sec Pulse Width, 10% Duty Cycle	$R_{\theta JC}$	0.11 0.12	°C/W

- Continuous use at maximum temperature will affect MTTF.
- MTTF calculator available at <http://www.freescale.com/rf>. Select Software & Tools/Development Tools/Calculators to access MTTF calculators by product.
- Refer to AN1955, *Thermal Measurement Methodology of RF Power Amplifiers*. Go to <http://www.freescale.com/rf>. Select Documentation/Application Notes - AN1955.

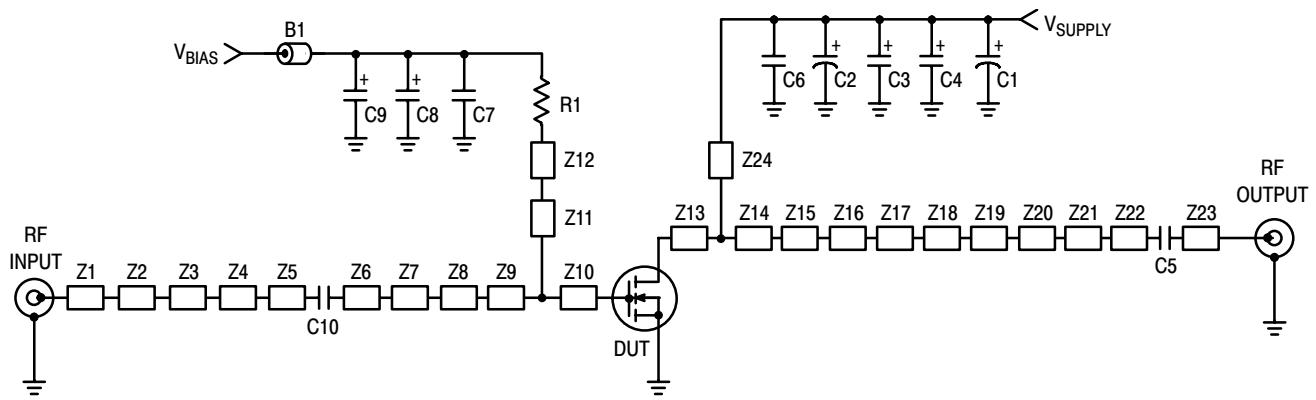
Table 3. ESD Protection Characteristics

Test Methodology	Class
Human Body Model (per JESD22-A114)	1C (Minimum)
Machine Model (per EIA/JESD22-A115)	A (Minimum)
Charge Device Model (per JESD22-C101)	IV (Minimum)

Table 4. Electrical Characteristics ($T_C = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
Off Characteristics					
Gate-Source Leakage Current ($V_{GS} = 5 \text{ Vdc}$, $V_{DS} = 0 \text{ Vdc}$)	I_{GSS}	—	—	1	$\mu\text{A dc}$
Zero Gate Voltage Drain Leakage Current ($V_{DS} = 32 \text{ Vdc}$, $V_{GS} = 0 \text{ Vdc}$)	I_{DSS}	—	—	1	$\mu\text{A dc}$
Zero Gate Voltage Drain Leakage Current ($V_{DS} = 65 \text{ Vdc}$, $V_{GS} = 0 \text{ Vdc}$)	I_{DSS}	—	—	10	$\mu\text{A dc}$
On Characteristics					
Gate Threshold Voltage ($V_{DS} = 10 \text{ Vdc}$, $I_D = 400 \mu\text{A dc}$)	$V_{GS(\text{th})}$	1.2	1.9	2.7	Vdc
Gate Quiescent Voltage ($V_{DD} = 32 \text{ Vdc}$, $I_D = 150 \text{ mA}$, Measured in Functional Test)	$V_{GS(Q)}$	1.5	2.4	3	Vdc
Drain-Source On-Voltage ($V_{GS} = 10 \text{ Vdc}$, $I_D = 2.0 \text{ Adc}$)	$V_{DS(\text{on})}$	0.1	0.17	0.3	Vdc
Dynamic Characteristics ⁽¹⁾					
Reverse Transfer Capacitance ($V_{DS} = 32 \text{ Vdc} \pm 30 \text{ mV(rms)ac}$ @ 1 MHz, $V_{GS} = 0 \text{ Vdc}$)	C_{rss}	—	0.87	—	pF
Output Capacitance ($V_{DS} = 32 \text{ Vdc} \pm 30 \text{ mV(rms)ac}$ @ 1 MHz, $V_{GS} = 0 \text{ Vdc}$)	C_{oss}	—	464	—	pF
Input Capacitance ($V_{DS} = 32 \text{ Vdc}$, $V_{GS} = 0 \text{ Vdc} \pm 30 \text{ mV(rms)ac}$ @ 1 MHz)	C_{iss}	—	214	—	pF
Functional Tests (In Freescale Test Fixture, 50 ohm system) $V_{DD} = 32 \text{ Vdc}$, $I_{DQ} = 150 \text{ mA}$, $P_{out} = 120 \text{ W Peak}$ (24 W Avg.), $f = 3100 \text{ MHz}$ and $f = 3500 \text{ MHz}$, Pulsed, 100 μsec Pulse Width, 20% Duty Cycle, 25 ns Input Rise Time					
Power Gain	G_{ps}	10.5	12	13.5	dB
Drain Efficiency	η_D	38	40	—	%
Input Return Loss	IRL	—	-15	-8	dB
Pulsed RF Performance (In Freescale Application Test Fixture, 50 ohm system) $V_{DD} = 32 \text{ Vdc}$, $I_{DQ} = 150 \text{ mA}$, $P_{out} = 120 \text{ W Peak}$ (24 W Avg.), $f = 3100 \text{ MHz}$ and $f = 3500 \text{ MHz}$, Pulsed, 100 μsec Pulse Width, 20% Duty Cycle, 25 ns Input Rise Time					
Output Pulse Droop (500 μsec Pulse Width, 10% Duty Cycle)	DRP_{out}	—	0.3	—	dB
Load Mismatch Tolerance (VSWR = 10:1 at all Phase Angles)	VSWR-T	No Degradation in Output Power			

1. Part internally matched both on input and output.



Z1 0.120" x 0.082" Microstrip
 Z2* 0.094" x 0.310" Microstrip
 Z3* 0.3502" x 0.082" Microstrip
 Z4 0.120" x 0.629" Microstrip
 Z5, Z22 0.050" x 0.082" Microstrip
 Z6 0.052" x 0.082" Microstrip
 Z7 0.084" x 0.436" Microstrip
 Z8 1.142" x 0.082" Microstrip
 Z9 0.144" x 0.564" Microstrip
 Z10 0.078" x 0.564" Microstrip
 Z11 0.048" x 1.349" Microstrip
 Z12 0.120" x 0.175" Microstrip
 Z13 0.087" x 0.576" Microstrip

Z14 0.390" x 0.576" Microstrip
 Z15 0.202" x 0.082" Microstrip
 Z16 0.066" x 0.162" Microstrip
 Z17 0.084" x 0.330" Microstrip
 Z18 0.105" x 0.082" Microstrip
 Z19 0.080" x 0.147" Microstrip
 Z20 0.366" x 0.082" Microstrip
 Z21 0.070" x 0.207" Microstrip
 Z23 0.734" x 0.082" Microstrip
 Z24 0.071" x 0.477" Microstrip
 PCB Arlon CuClad 250GX-0300-55-22, 0.030", $\epsilon_r = 2.55$
 * Line length includes microstrip bends

Figure 1. MRF7S35120HSR3 Test Circuit Schematic

Table 5. MRF7S35120HSR3 Test Circuit Component Designations and Values

Part	Description	Part Number	Manufacturer
B1	47 Ω, 100 MHz Short Ferrite Bead	2743019447	Fair-Rite
C1	470 μF, 63 V Electrolytic Capacitor	477KXM063M	Illinois Cap.
C2	47 μF, 50 V Electrolytic Capacitor	476KXM050M	Illinois Cap.
C3, C4	22 μF, 35 V Tantalum Capacitors	T491X226K035AT	Kemet
C5	3.3 pF Chip Capacitor	ATC100B3R3CT500XT	ATC
C6, C7, C10	2.7 pF Chip Capacitors	ATC100B2R7BT500XT	ATC
C8, C9	22 μF, 25 V Tantalum Capacitors	ECS-T1ED226R	Panasonic TE series
R1	51 Ω, 1/4 W Chip Resistor	CRCW120651R0FKEA	Vishay

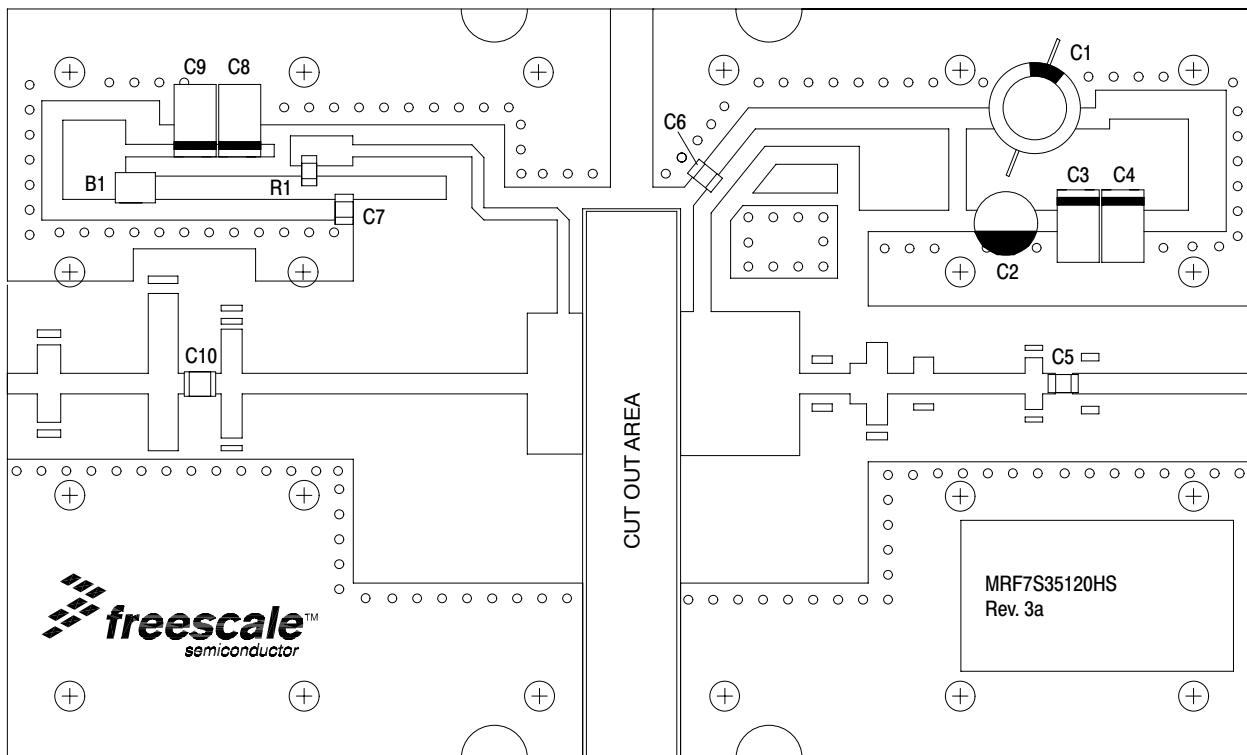
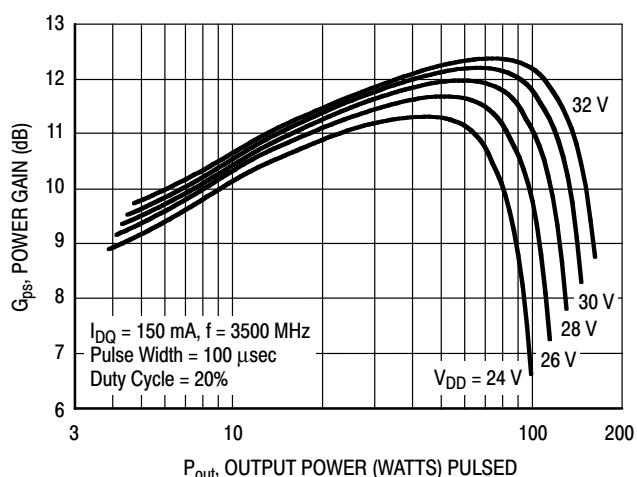
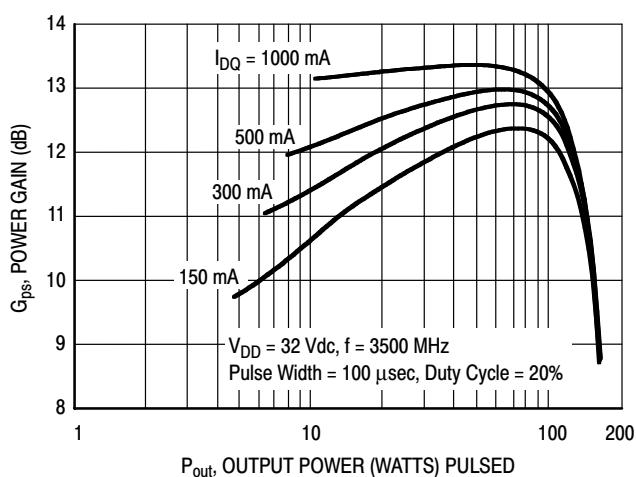
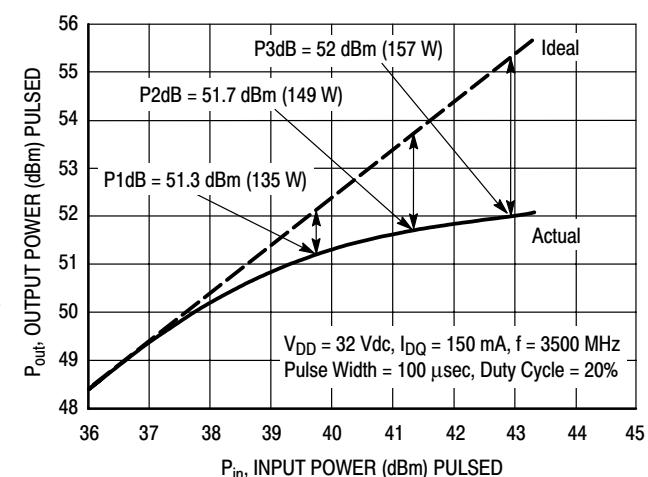
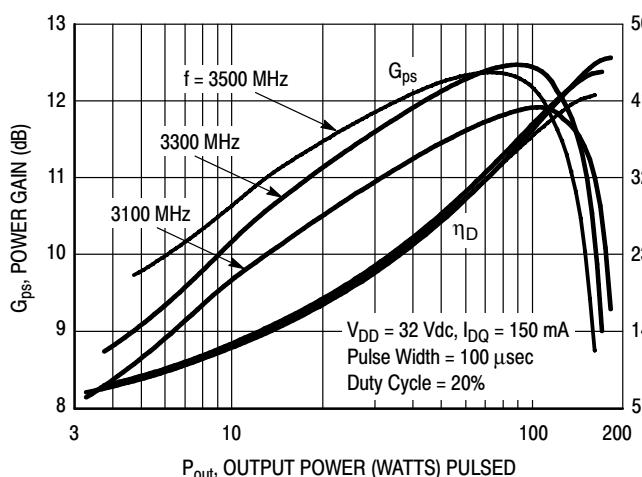
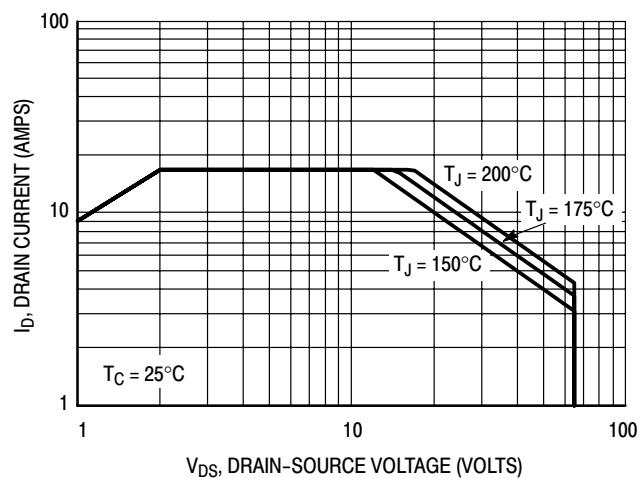
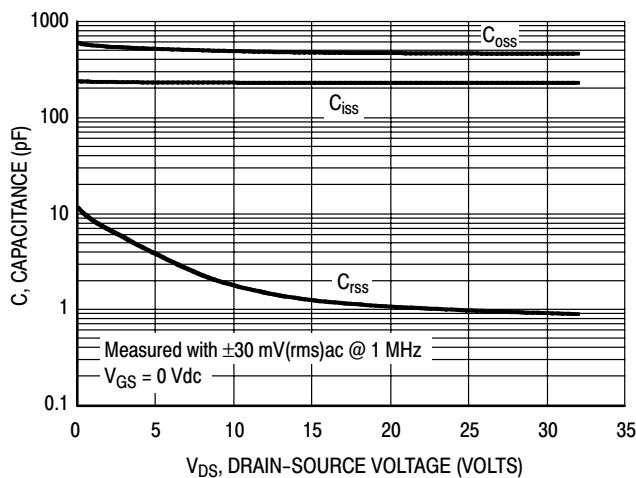
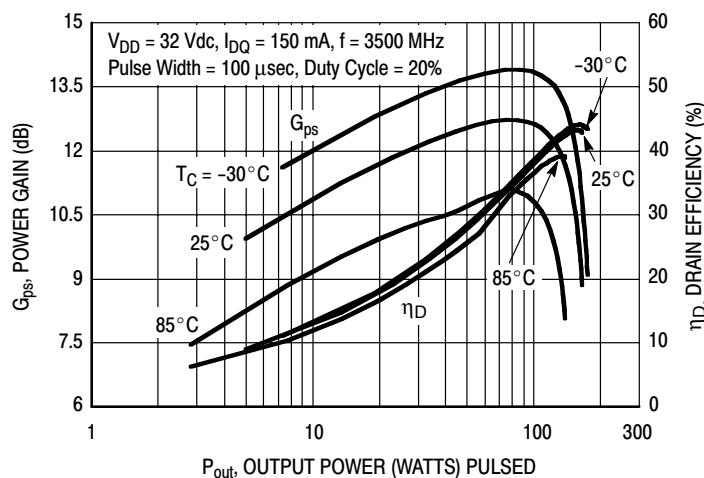
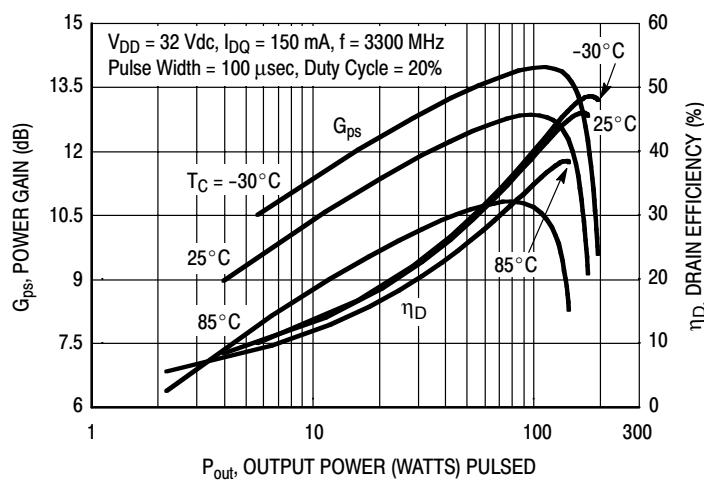
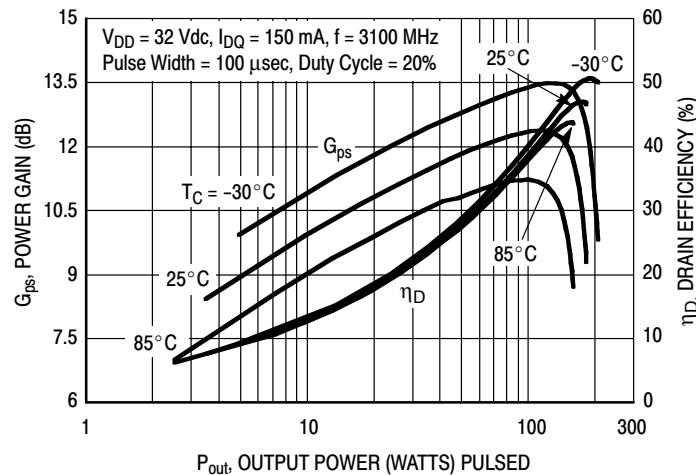
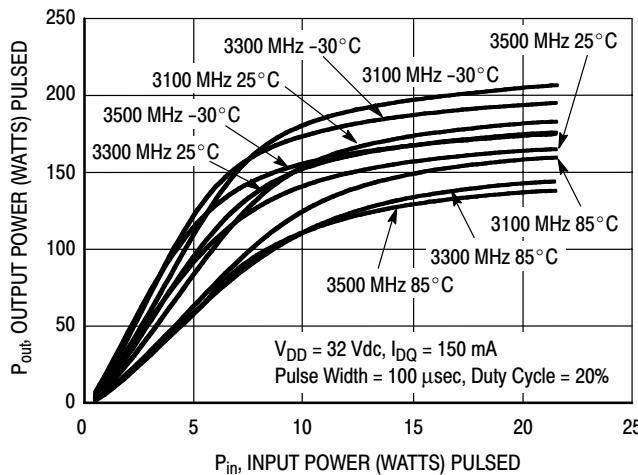


Figure 2. MRF7S35120HSR3 Test Circuit Component Layout

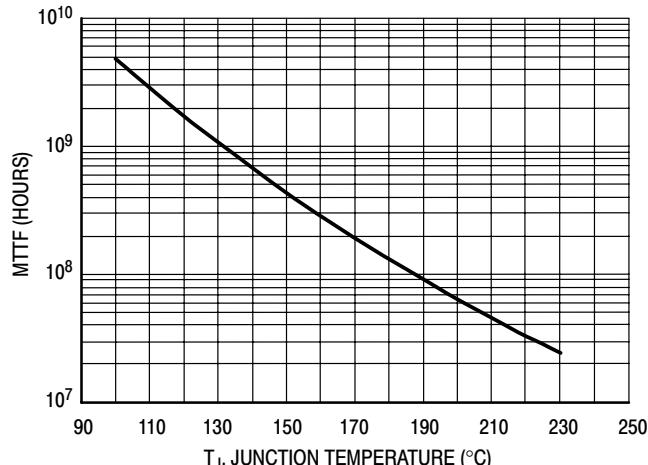
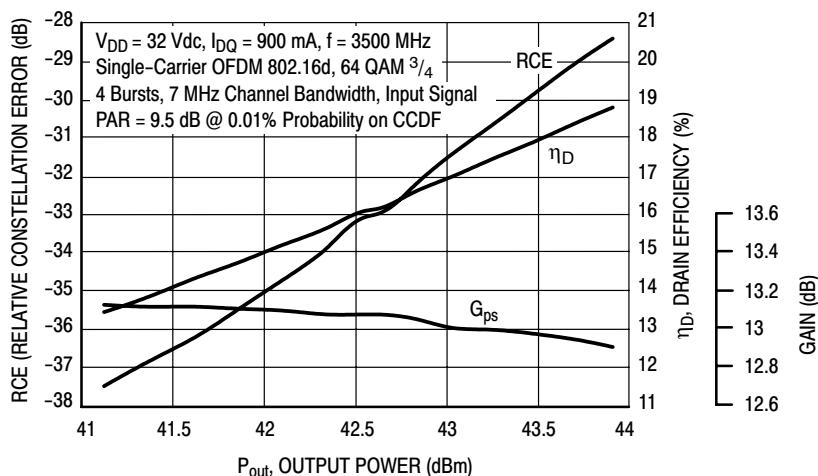
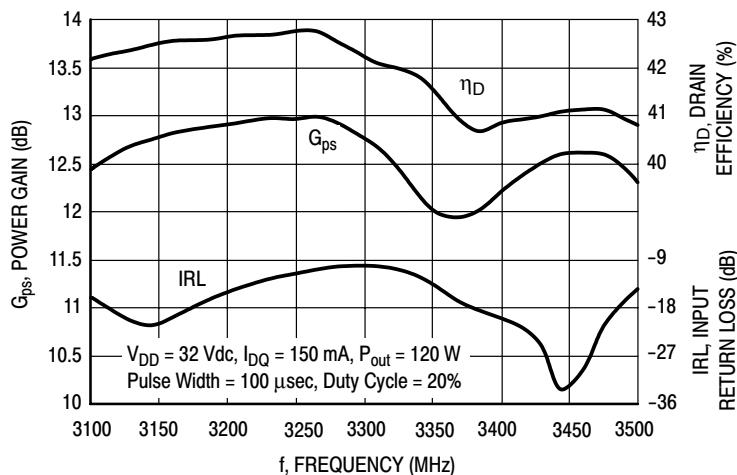
TYPICAL CHARACTERISTICS



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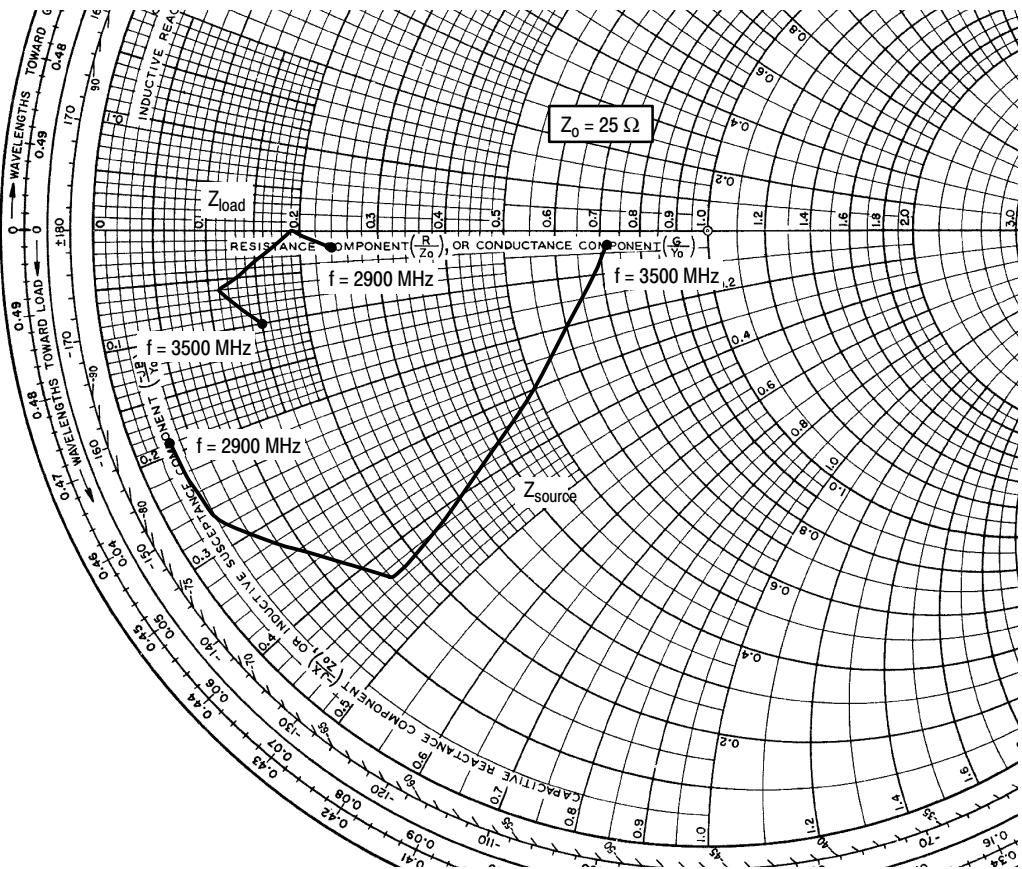


This above graph displays calculated MTTF in hours when the device is operated at $V_{DD} = 32$ Vdc, $P_{out} = 120$ W Peak, Pulse Width = 100 μ sec, Duty Cycle = 20%, and $\eta_D = 40\%$.

MTTF calculator available at <http://www.freescale.com/rf>. Select Software & Tools/Development Tools/Calculators to access MTTF calculators by product.

Figure 15. MTTF versus Junction Temperature

MRF7S35120HSR3



$V_{DD} = 32 \text{ Vdc}, I_{DQ} = 150 \text{ mA}, P_{out} = 120 \text{ W Peak}$

f MHz	Z_{source} Ω	Z_{load} Ω
2900	$0.825 - j4.72$	$6.03 - j0.487$
3100	$1.1 - j6.74$	$4.63 - j0.0472$
3300	$3.95 - j10.8$	$2.65 - j1.44$
3500	$18 - j1.1$	$3.65 - j2.56$

Z_{source} = Test circuit impedance as measured from gate to ground.

Z_{load} = Test circuit impedance as measured from drain to ground.

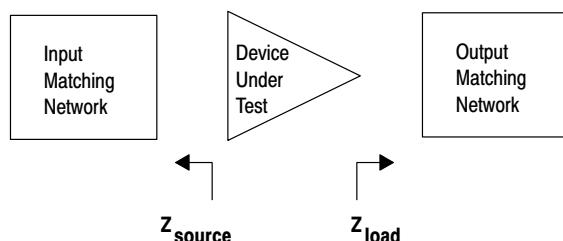
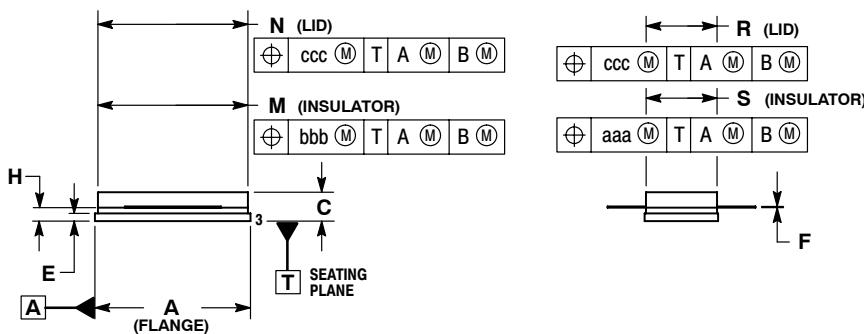
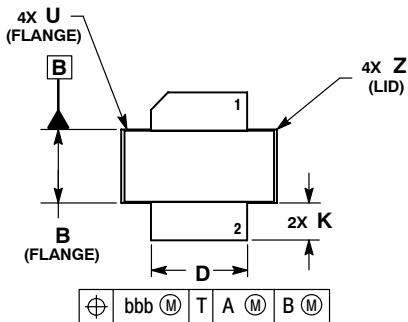


Figure 16. Series Equivalent Source and Load Impedance

PACKAGE DIMENSIONS



NOTES:

1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M-1994.
2. CONTROLLING DIMENSION: INCH.
3. DELETED
4. DIMENSION H IS MEASURED 0.030 (0.762) AWAY FROM PACKAGE BODY.

DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.805	0.815	20.45	20.70
B	0.380	0.390	9.65	9.91
C	0.125	0.170	3.18	4.32
D	0.495	0.505	12.57	12.83
E	0.035	0.045	0.89	1.14
F	0.003	0.006	0.08	0.15
H	0.057	0.067	1.45	1.70
K	0.170	0.210	4.32	5.33
M	0.774	0.786	19.61	20.02
N	0.772	0.788	19.61	20.02
R	0.365	0.375	9.27	9.53
S	0.365	0.375	9.27	9.52
U	---	0.040	---	1.02
Z	---	0.030	---	0.76
aaa	0.005 REF		0.127 REF	
bbb	0.010 REF		0.254 REF	
ccc	0.015 REF		0.381 REF	

STYLE 1:
 PIN 1. DRAIN
 2. GATE
 5. SOURCE

CASE 465A-06
ISSUE H
NI-780S

MRF7S35120HSR3

PRODUCT DOCUMENTATION

Refer to the following documents to aid your design process.

Application Notes

- AN1955: Thermal Measurement Methodology of RF Power Amplifiers

Engineering Bulletins

- EB212: Using Data Sheet Impedances for RF LDMOS Devices

REVISION HISTORY

The following table summarizes revisions to this document.

Revision	Date	Description
0	May 2008	<ul style="list-style-type: none">• Initial Release of Data Sheet
1	June 2008	<ul style="list-style-type: none">• Corrected P_{out} error and changed from 42.5 Watts to 18 Watts, Typical WiMAX Performance bullet, p. 1

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